

Kelvin probe force microscopy : measuring and compensating electrostatic forces

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Deskripsi Lengkap: <https://lib.ui.ac.id/detail?id=20405909&lokasi=lokal>

Abstrak

This book gives a concise introduction into the method and describes various experimental techniques. Surface potential studies on semiconductor materials, nanostructures and devices are described, as well as application to molecular and organic materials. The current state of surface potential at the atomic scale is also considered.